## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

ANDRADE ET AL.

Examiner

09841644

Parry, Chris

Art Unit

2623

Notes	Date	Examiner
SEE ATTACHED SEARCH HISTORY FROM EAST.	6/3/2005	CLP
CONSULTED HAI TRAN ON AREAS OF SEARCH IN CLASS 725.	5/31/2005	CLP
CONSULTED JOHN MILLER ON AREAS OF SEARCH IN CLASS 725.	5/25/2005	CLP
SEE UPDATED ATTACHED SEARCH HISTORY FROM EAST.	10/25/2005	CLP
CONSULTED SCOTT BELIVEAU (RE: CLAIM 1).	10/31/2005	CLP
SEE UPDATED ATTACHED SEARCH HISTORY FROM EAST.	7/6/2006	CLP
DISCUSSED AT QEM	7/5/2006	CLP
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Class	SubClass	Date		Examiner
725	109-114	5/25/2005	CLP	
725	136-142	5/31/2005	CLP	
725	18-19	6/2/2005	CLP	
709	217-219	5/25/2005	CLP	
JPDATED	ABOVE	10/25/2005	CLP	
JPDATED	ABOVE	7/6/2006	CLP	
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